

SN54ALS1010A, SN74ALS1010A TRIPLE 3-INPUT POSITIVE-NAND BUFFERS

SDAS075A – D2661, APRIL 1982 – REVISED MAY 1986

- Buffer Version of 'ALS10A
- Package Options include Plastic Small Outline DIPs and Ceramic Chip Carriers in Addition to the Standard 300-mil Plastic and Ceramic DIPs.
- Dependable Texas Instruments Quality and Reliability

description

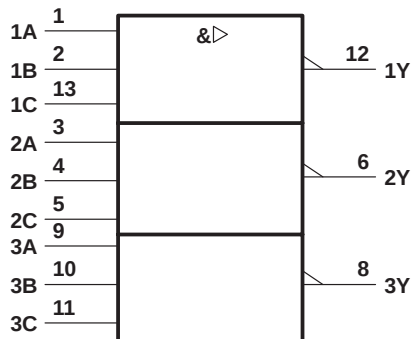
These devices contain three independent 3-input NAND buffers. They perform the Boolean functions $Y = \overline{A \cdot B \cdot C}$ or $Y = A + B + C$ in positive logic.

The SN54ALS1010A is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ALS1010A is characterized for operation from 0°C to 70°C .

FUNCTION TABLE
(each gate)

INPUTS			OUTPUT
A	B	C	Y
H	H	H	L
L	X	X	H
X	L	X	H
X	X	L	H

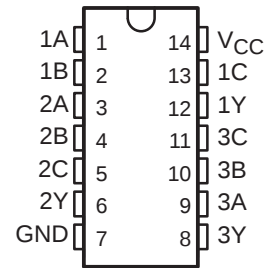
logic symbol †



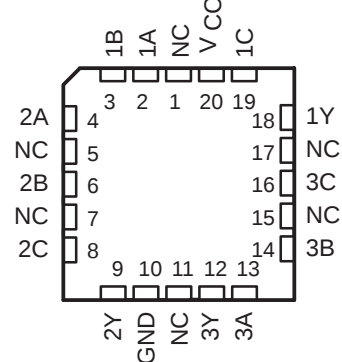
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, and N packages.

SN54ALS1010A ... J PACKAGE
SN74ALS1010A ... D OR N PACKAGE
(TOP VIEW)

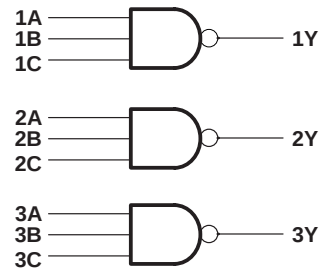


SN54ALS1010A ... FK PACKAGE
(TOP VIEW)



NC – No internal connection

logic diagram (positive logic)



SN54ALS1010A, SN74ALS1010A

TRIPLE 3-INPUT POSITIVE-NAND BUFFERS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC}	7 V
Input voltage	7 V
Operating free-air temperature range:	SN54ALS1010A –55°C to 125°C
	SN74ALS1010A 0°C to 70°C
Storage temperature range	–65°C to 150°C

recommended operating conditions

		SN54ALS1010A			SN74ALS1010A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
I_{OH}	High-level output current			–1			–2.6	mA
I_{OL}	Low-level output current			12			24	mA
T_A	Operating free-air temperature	–55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54ALS1010A			SN74ALS1010A			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}	$V_{CC} = 4.5$ V, $I_I = -18$ mA				–1.5			–1.5	V
V_{OH}	$V_{CC} = 4.5$ V to 5.5 V, $I_{OH} = -0.4$ mA		$V_{CC}-2$			$V_{CC}-2$			V
	$V_{CC} = 4.5$ V, $I_{OH} = -1$ mA		2.4	3.3					
	$V_{CC} = 4.5$ V, $I_{OH} = -2.6$ mA					2.4	3.3		
V_{OL}	$V_{CC} = 4.5$ V, $I_{OL} = 12$ mA			0.25	0.4		0.25	0.4	V
	$V_{CC} = 4.5$ V, $I_{OL} = 24$ mA						0.35	0.5	
I_I	$V_{CC} = 5.5$ V, $V_I = 7$ V				0.1			0.1	mA
I_{IH}	$V_{CC} = 5.5$ V, $V_I = 2.7$ V				20			20	µA
I_{IL}	$V_{CC} = 5.5$ V, $V_I = 0.4$ V				–0.1			–0.1	mA
$I_{O}^{\ddagger}$	$V_{CC} = 5.5$ V, $V_O = 2.25$ V		–30		–112	–30		–112	mA
I_{CCH}	$V_{CC} = 5.5$ V, $V_I = 0$			0.65	1.2		0.65	1.2	mA
I_{CCL}	$V_{CC} = 5.5$ V, $V_I = 4.5$ V			3.6	5.8		3.6	5.8	mA

† All typical values are at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$.

‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .

switching characteristics (see Note 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, C _L = 50 pF, R _L = 500 Ω, T _A = 25°C	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX				UNIT
			'ALS1010A	SN54ALS1010A		SN74ALS1010A		
			TYP	MIN	MAX	MIN	MAX	
t _{PLH}	A or B	Y	5	2	12	2	8	ns
t _{PHL}			5	2	12	2	8	

NOTE 1: Load circuit and voltage waveforms are shown in Section 1.



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